### **Description**

#### **N-channel Enhancement Mode Power MOSFET**

#### **Features**

- 100V, 3.8A
  - $R_{DS(ON)}$  < 286 m $\Omega$  @  $V_{GS}$  = 10 V  $R_{DS(ON)}$  < 325 m $\Omega$  @  $V_{GS}$  = 4.5 V
- Advanced Trench Technology
- Excellent R<sub>DS(ON)</sub> and Low Gate Charge
- Lead Free

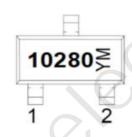
#### **Applications**

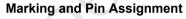
- Load Switch
- PWM Application
- Power Management

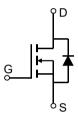












**Schematic Diagram** 

#### Package Marking and Ordering Information

Device Marking	Device	Outline	Package	Reel Size	Reel(pcs)	Per Carton (pcs)
10280	CRMJTL10280A	TAPING	SOT-23-3L	7"	3000	120000

### Absolute Maximum Ratings (@ T<sub>C</sub> = 25°C unless otherwise specified)

Symbol	Parameter		Value	Units	
V <sub>DS</sub>	Drain-to-Source Voltage		100	V	
$V_{GS}$	Gate-to-Source Voltage		±20	V	
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> = 25°C	3.8	A	
		T <sub>C</sub> = 100°C	2.4		
I <sub>DM</sub>	Pulsed Drain Current (1)		15	А	
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C	2.3	W	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient		54	°C/W	
$T_J$ , $T_{STG}$	Junction & Storage Temperature Range		-55 to 150	°C	

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#### **Electrical Characteristics** (T<sub>J</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	aracteristics					
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V	-	-	1.0	μА
I <sub>GSS</sub>	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0	1.5	2.2	V
	(2)	V <sub>GS</sub> = 10V, I <sub>D</sub> = 2A	-	220	286	mΩ
$R_{DS(ON)}$	Static Drain-Source ON-Resistance <sup>(2)</sup>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 1A	-	250	325	mΩ
Dynam	ic Characteristics					
C <sub>iss</sub>	Input Capacitance		- /	321	-	pF
$C_{oss}$	Output Capacitance	$V_{GS} = 0V, V_{DS} = 25V,$ f = 1MHz		21	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	15	-	pF
Q <sub>g</sub>	Total Gate Charge			5.3	-	nC
$Q_{gs}$	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 30V, I_{D} = 2A$	<u></u> )-	1.3	-	nC
$Q_{gd}$	Gate Drain("Miller") Charge	V <sub>DS</sub> - 30V, I <sub>D</sub> -2A	-	1.7	-	nC
Switch	ing Characteristics					
t <sub>d(on)</sub>	Turn-On DelayTime		-	14	-	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 30V$	-	54	-	ns
$t_{d(off)}$	Turn-Off DelayTime	$I_D = 1A, R_{GEN} = 3\Omega$	-	18	-	ns
t <sub>f</sub>	Turn-Off Fall Time	) `	-	11	-	ns
Drain-S	Source Diode Characteristics and M	Max Ratings				
Is	Maximum Continuous Drain to Source Diode Forward Current			-	3.8	А
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	15.2	А
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 3A$	-	-	1.2	V

Notes:

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<sup>1.</sup> Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

<sup>2.</sup> Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  0.5%.

## **Typical Performance Characteristics**

Figure 1: Output Characteristics

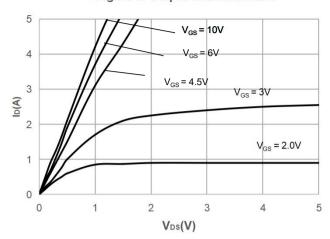


Figure 2: Typical Transfer Characteristics

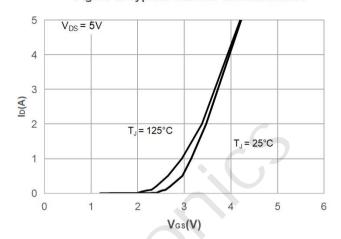


Figure 3: On-resistance vs. Drain Current

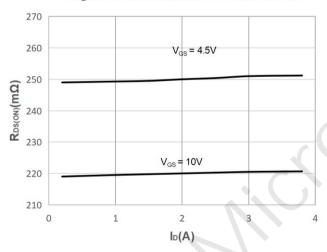


Figure 4: Body Diode Characteristics

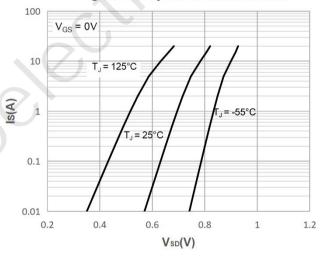


Figure 5: Gate Charge Characteristics

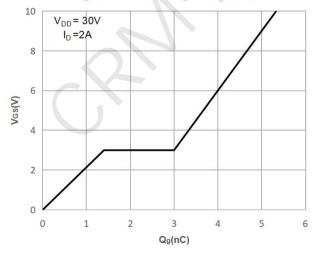
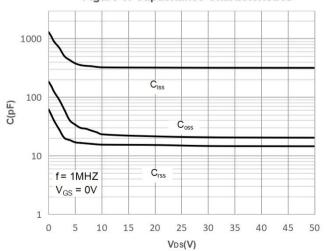


Figure 6: Capacitance Characteristics





## **Typical Performance Characteristics**

Figure 7: Normalized Breakdown voltage vs.
Junction Temperature

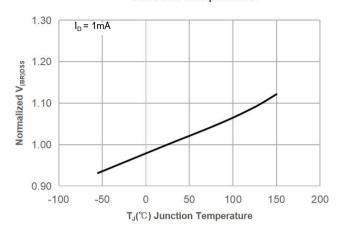


Figure 8: Normalized on Resistance vs. Junction Temperature

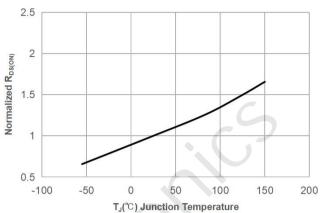


Figure 9: Maximum Safe Operating Area

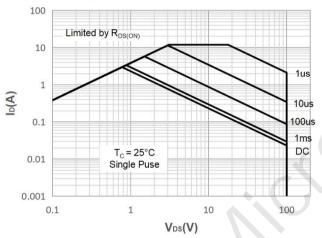


Figure 10: Maximum Continuous Drian Current vs. Case Temperature

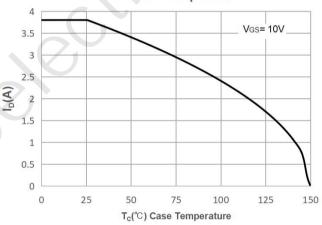


Figure 11: Normalized Maximum Transient Thermal Impedance

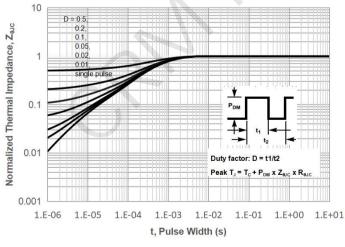
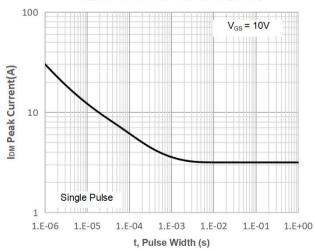


Figure 12: Peak Current Capacity





### **Test Circuit**

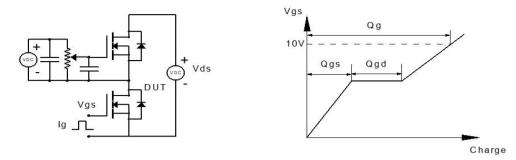


Figure 1: Gate Charge Test Circuit & Waveform

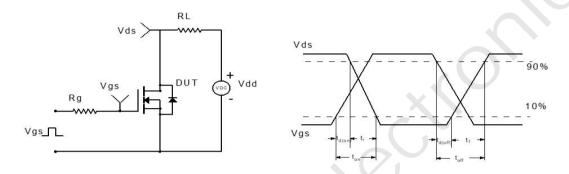


Figure 2: Resistive Switching Test Circuit & Waveform

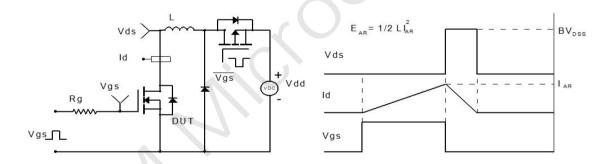


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

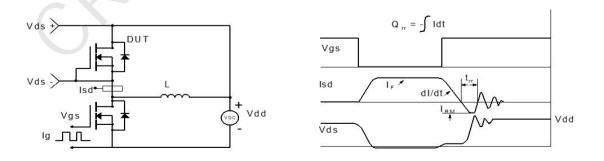
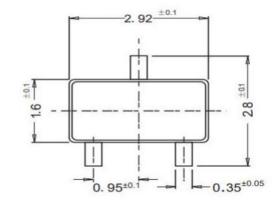


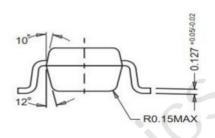
Figure 4: Diode Recovery Test Circuit & Waveform

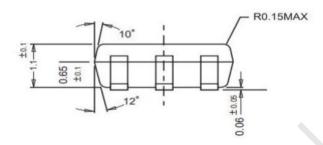




### Package Mechanical Data(SOT-23-3L)







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